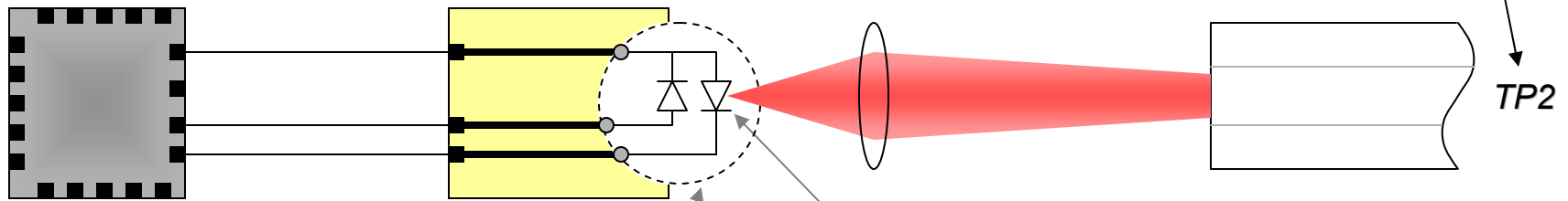


TP2 Impairments and tests

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TP2 components & impairments

Specification defined only at TP2
(everything else is implementation detail)



<u>Clock</u>	<u>Driver</u>	<u>Interconnect</u>	<u>Attach</u>	<u>Package</u>	<u>E/O</u>	<u>Optics</u>	<u>MMF</u>
<ul style="list-style-type: none"> • Crystal • Synth 	<ul style="list-style-type: none"> • III-V • SiGe • CMOS 	<ul style="list-style-type: none"> • Rogers, etc. • FR-4 	<ul style="list-style-type: none"> • Flex • Leads 	<ul style="list-style-type: none"> • Microwave • TO-can 	<ul style="list-style-type: none"> • EML • DFB • FP • VCSEL 	<ul style="list-style-type: none"> • Isolator • Lens 	<ul style="list-style-type: none"> • <i>Launch conditions outside scope</i>
<ul style="list-style-type: none"> • RJ • Other jitter 	<ul style="list-style-type: none"> • Edge rates • Overshoot and ringing • RJ & other jitter • DDJ • DCD • Additive noise 	<p><u>Electrical coupling</u></p> <ul style="list-style-type: none"> • Frequency loss • Reflections and resonances • Crosstalk pickup 		<p><u>Laser</u></p> <ul style="list-style-type: none"> • Edge rates • Overshoot and ringing • DCD • <i>Difference</i> in rising and falling edges rates • <i>Difference</i> in overshoot and ringing • RIN on logic 1 • RIN on logic 0 • Spectrum (λ dispersion) 	<p><u>Optics</u></p> <ul style="list-style-type: none"> • Geom dynamics? • λ dynamics? 		

Categorization of impairments

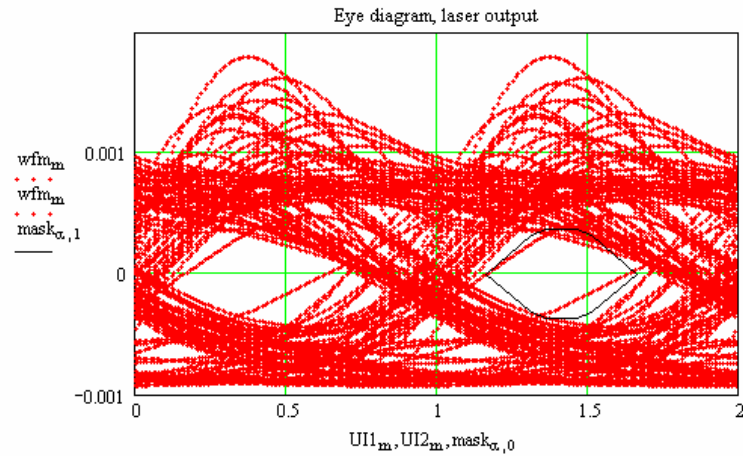
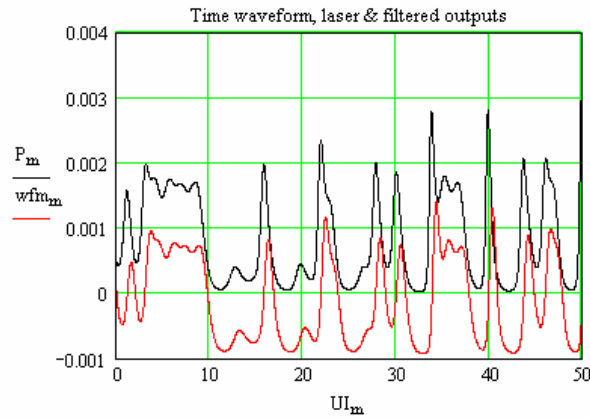
		Correlated	Uncorrelated	Correctable	Uncorrectable
Clocking	RJ		X		X
	Other contributed jitter		X		X
Driver	Edge rates	X		X	
	Overshoot and ringing	X		?	
	Contributed RJ & other jitter		X		X
	Contributed DDJ	X		X	
	DCD	X			X
	Additive noise		X		X
Electrical coupling	Frequency loss	X		X	
	Reflections and resonances	X		?	
	Crosstalk pickup		X	?	
Laser	Edge rates	X		X	
	Overshoot and ringing	X		X	
	DCD	X			X
	Difference in rising and falling edges rates	X			X
	Difference in overshoot and ringing	X			X
	RIN on logic 1		X		X
	RIN on logic 0		X		X
Optical coupling	Spectral dispersion	X		X	
	Geometric dynamics?				
	Spectral dynamics?				

Categories require different tests?

- Proposal for correctable
 - Use scope averaged waveform capture for data dependent effects
 - Run waveform through simulated channel and simulated “standard” EDC Rx to determine power penalty vs. spec/limit
 - Easier than LR – does not HW dispersion, reference Rx, or reference Tx
 - Penalty vs. “perfect” Tx, same simulate channel
 - Relative test, so does it matter which channel? Is a channel even required?
 - Standard EDC Rx TBD
 - Use some portion of intermediate pattern per 802.3ae
 - TBD, penalty limit would be a function of exact pattern used
 - Requires pattern trigger (& perhaps sub-pattern recognition?)
 - Impose penalty back onto transmitter OMA (per TDP)?
- Proposal for uncorrectable
 - Use mask test
 - Similar complexity as for LR
 - Start with –LR mask?
 - Use square wave pattern per 802.3ae to avoid data dependent effects
 - Requires clock recovery trigger
 - Tighten X1 for uncorrelated jitter?
- Budget must account for both; specs/tests must align with budget

Examples

- PRBS pattern, penalty unknown



- Mask test with square wave, barely passes...

